Aehr Test Systems

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Aehr Test Systems to Announce Fourth Quarter Fiscal 2014 Financial Results on July 17, 2014

Fremont, CA (June 26, 2014) – Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced that it will report financial results for its fiscal 2014 fourth quarter ended May 31, 2014 on Thursday, July 17, 2014 following the close of the market. The Company will host a conference call and webcast at 5:00 p.m. Eastern time that afternoon to discuss the results.

What: Aehr Test Systems fourth quarter fiscal 2014 financial results conference call

When: Thursday, July 17th at 5:00 p.m. Eastern Time (2:00 p.m. PT)

Dial in Number: 888-427-9419 (US and Canada)

719-325-2458 (International)

Webcast: To access the live webcast, please visit the investor relations section at

www.aehr.com.

Call Replay: A phone replay of the call will be available approximately one hour following

the end of the call through 8:00 p.m. ET on Thursday, July 24, 2014.

Replay Numbers: 888-203-1112 (US and Canada)

719-457-0820 (International) Replay passcode: **8112057**#

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTSTM and FOXTM families of test and burnin systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.